



# YJP120G08A

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## N-Channel Enhancement Mode Field Effect Transistor

### Product Summary

$V_{DS}$	80V
$I_D$	120A
$R_{DS(ON)}$ ( at $V_{GS}=10V$ )	4.8



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## Electrical Characteristics (T<sub>J</sub>=25 unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250	80	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =80V, V <sub>GS</sub> =0V	-	-	1	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20V, V <sub>DS</sub> =0V	-	-	± 100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250	2.0	3.0	4.0	V
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	3.9	4.8	m
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =20A, V <sub>GS</sub> =0V	-	0.8	1.2	V
Maximum Body-Diode Continuous Current	I <sub>S</sub>		-	-	120	A
Gate resistance	R <sub>G</sub>	f=1MHz, Open drain	-	2	-	
Transconductance	G <sub>fs</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =50A		71.5		S
<b>Dynamic Parameters</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V, f=1MHz	-	5666	-	pF
Output Capacitance	C <sub>oss</sub>		-	860	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	7.5	-	
<b>Switching Parameters</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> =10V, I <sub>D</sub> =50A	-	73	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	25	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	12	-	
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =50A, di/dt=100A/us	-	50	-	
Reverse Recovery Time	t <sub>rr</sub>		-	44	-	
Turn-on Delay Time	t <sub>D(on)</sub>	V <sub>DS</sub> =40V, V <sub>GS</sub> I <sub>D</sub> =50A	-	27	-	ns
Turn-on Rise Time	t <sub>r</sub>		-	32	-	
Turn-off Delay Time	t <sub>D(off)</sub>		-	54	-	
Turn-off fall Time	t <sub>f</sub>		-	17	-	

A. Repetitive rating; pulse width limited by max. junction temperature.

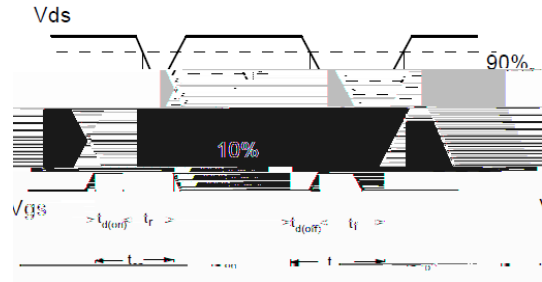
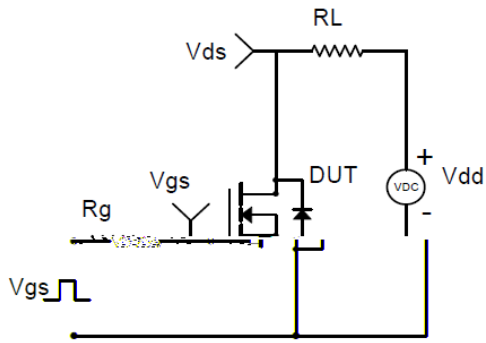
B. T<sub>J</sub>=25, V<sub>DD</sub>=50V, V<sub>GS</sub>=10V, L=2mH I<sub>as</sub>=26.5A.

C. P<sub>d</sub> is based on max. junction temperature, using junction-case thermal resistance.

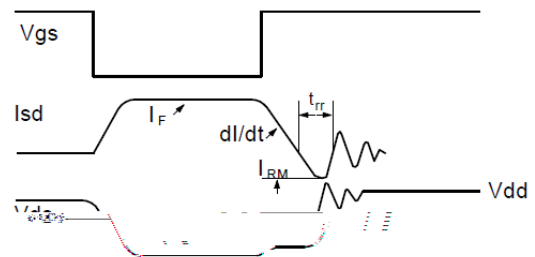
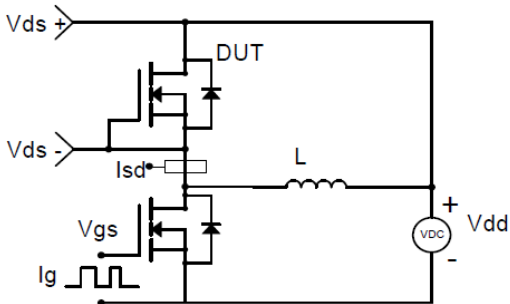
D. The value of R is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.



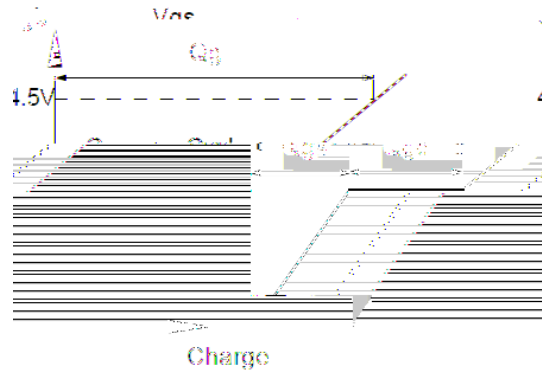




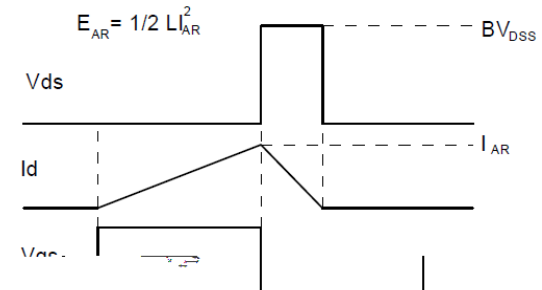
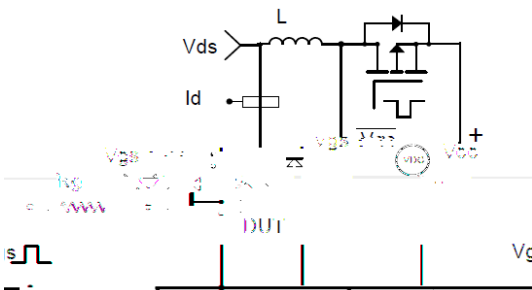
**Resistive Switching Test Circuit & Waveforms**



**Diode Recovery Test Circuit & Waveforms**



**Gate Charge Test Circuit & Waveform**

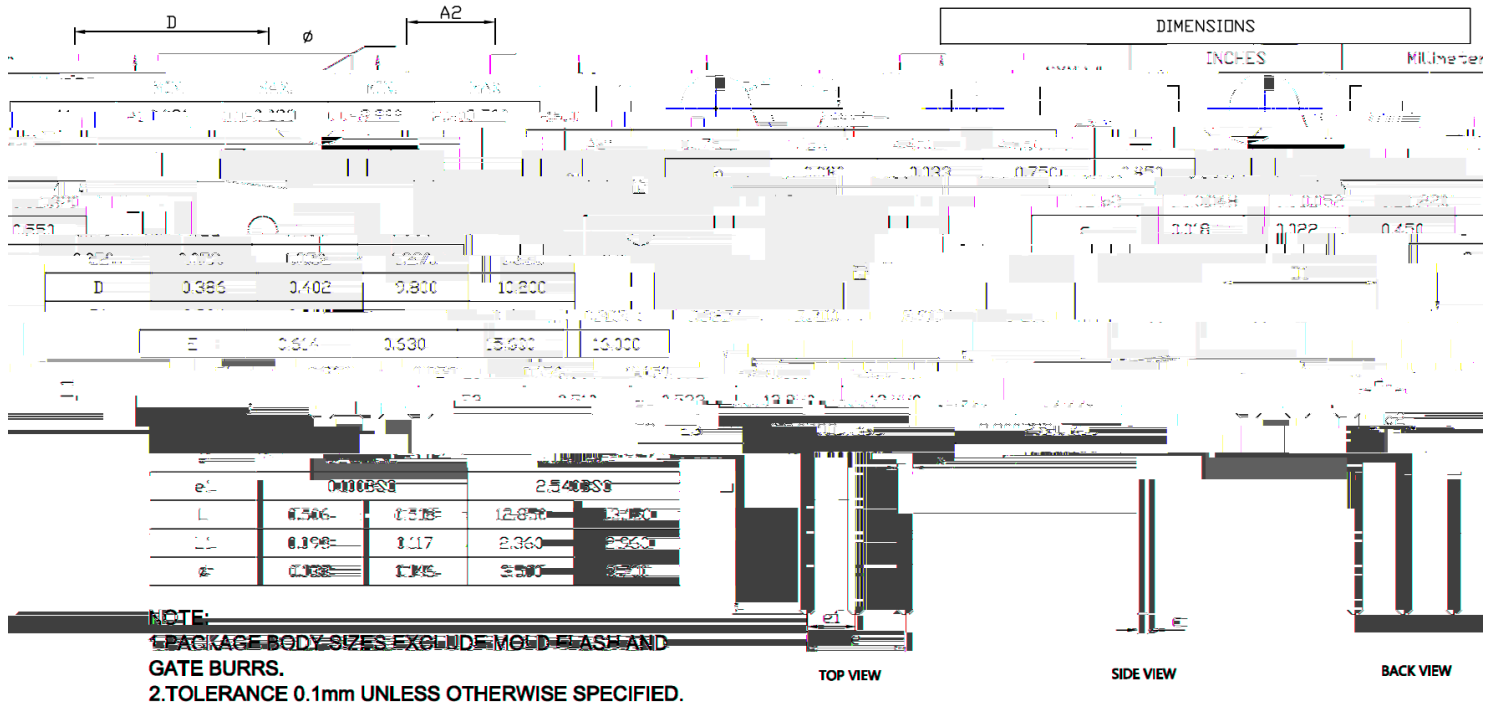


**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**



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## TO-220AB-D Package information





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